Application/Control No. Applicant(s)/Patent Under Reexamination 10/798,157 LI ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Sin J. Lee 1752 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY US-Α US-В С US-D US-Ε US-US-F G USн US-1 US-J US-Κ US-US-L М US-**FOREIGN PATENT DOCUMENTS Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R S Ŧ **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U Full, formal English translation of JP 2000-63433 (Iwasa et al), provided by USPTO. V W

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